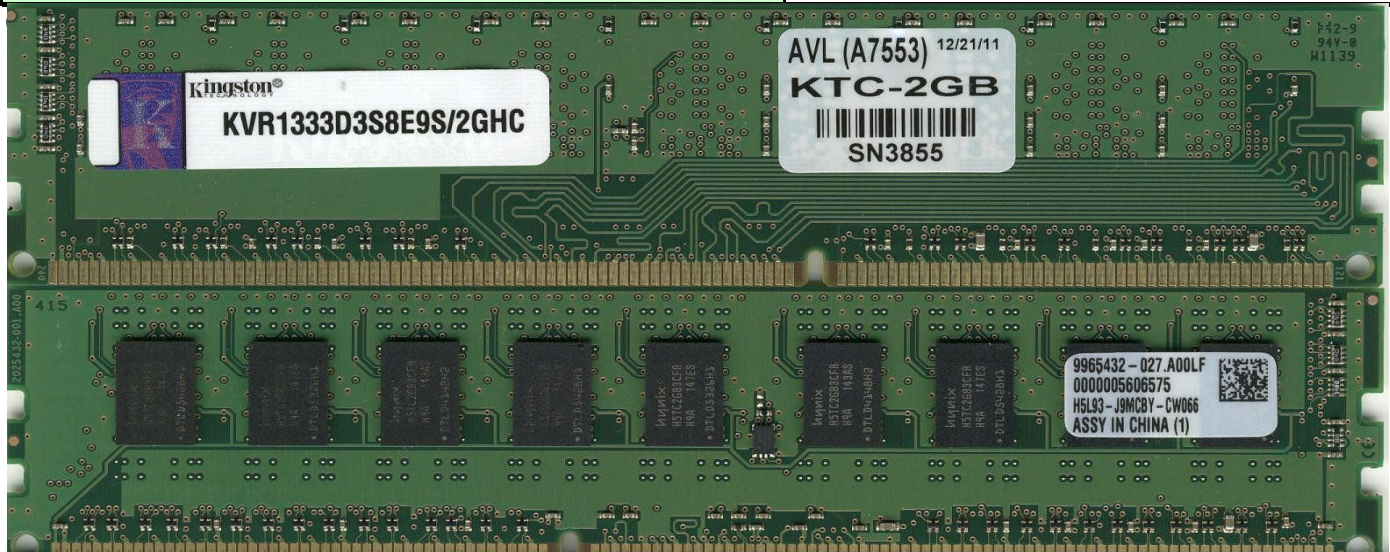
	AVL Supermicro server platform Memory Module Qualification Test		
	Intel X5650(WSM) x 2, Intel 5520 (Tylersburg), Rev B3	Test Results	Pass
	PN: KVR1333D3S8E9S/2GB (2GB / UDIMM ECC / ECC) On: X8DT6-F Rev.1.3		

RP77D3x-106-KI-SQ-SMC-V1		Module Information		Rev 01/07/2011
AVL WorkOrder #	WC2582	AVL A#	7553	
Start Date	12/30/2011	End Date	1/3/2012	
Tested By	Van N			
Module Manufacturer	Kingston			
Module Part Number	KVR1333D3S8E9S/2GB			
Module BOM Number	9965432-027.A00			
Module Capacity / Memory Type / ECC	2GB / UDIMM ECC/ ECC			
Module Configuration (Width, # of devices, # of Ranks)	256Mx72 /9 Devices / 1 Rank			
Speed Tested (Data rate of Mbps, CL-tRP-tRCD)	DDR3-1333 /9-9-9			
DRAM Device Vendor	Hynix			
DRAM Device Part Number / Date code	H5TC2G83CFR-H9A	1147		
DRAM Die Revision / Process Technology (nm)	C			
DRAM Device Config (Density / Width)	2Gbit / x8			
Thermal Sensor Device Vendor / Part Number / Revision				
Register Device Vendor / Part Number / Revision				



Platform System Information				
Motherboard Info (Model# & MB Revision & MB S/N & AVL S/N)	X8DT6-F	1.3	VMAS59161	SK4375
BISO Revision / BIOS Date / MRC Rev.	2.0a	9/14/2010	2.11	
CPU / Speed	Intel X5650(WSM) x 2		2.66GHz	
Chipset info (Stepping)	Intel 5520 (Tylersburg), Rev B3			



AVL Supermicro server platform Memory Module Qualification Test

Intel X5650(WSM) x 2, Intel 5520 (Tylersburg), Rev B3

PN: KVR1333D3S8E9S/2GB (2GB / UDIMM ECC / ECC) On: X8DT6-F Rev.1.3

Test Results:

PASS

Comments:

AVL Memory Module Qual Test Results Summary

Test # and name	Test Description	Specs	Test Results	Comments
1. Latest BIOS Upgrade & Configuration	Download / Upgrade latest BIOS & record size and speed detection	Per test platform, DIMM & config spec	Done	Record memory size & speed at each test only
2. SPD Check	Memory module SPD content check for JEDEC compliance	JEDEC	Pass	Use proprietary tools
3. Sisoftware Sandra Benchmark	Run Windows based diags & utility software @50°C - DIMM max loading.	1 loop per config	Done	Full load per spec
4. Passmark Burn-In		6 Hour per config	Pass	Full load per spec
5a. Stress Application Test	Run Linux based diags & utility software @50°C - DIMM max loading.	8 Hour per config	Pass	Full load per spec
5b. Stream Benchmark Test		5 loop per config	Done	Full load per spec
5c. Reset Cycle		500 loop per config	Pass	Full load per spec
6a. Functional Stress Test (Corner 1a)	Run RST Premium @50°C - DIMM max loading.	8 Hour or 2+ Loops per config	Pass	Full load per spec
6b. Functional Stress Test (Corner 1b)*	Run RST Premium @55°C - DIMM loading depends on @speed configuration	8 Hour or 2+ Loops per config	N/A	Per platform memory speed configuration table if different (run @Max module speed)
7. Functional Stress Test (Corner 2)	Run RST Premium @0°C DIMM max loading	8 Hour or 2+ Loops per config	N/A	Full load per spec

Note: All test under IMC Vdd=Nom, Vref=Vddnom/2

* Corner 1b test is not required if Corner 1A already covers max module speed.